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IN THE CLAIMS

- 1. (Currently amended) An integrated circuit (IC)-comprising a signal transmission channel (TX)-including radio frequencies and an integrated tester (TEST)-intended to test radio characteristics of said integrated circuit, said tester (TEST)-comprising: first means (COUPL) for recovering a part of the signal generated by the transmission channel (TX) at a first frequency (F0), second means (M)-for converting said recovered signal from the first frequency (F0)-into a second frequency (F1), an amplifier (A)-for amplifying said signal at this second frequency (F1), and a rectifier (R)-for rectifying said signal.
- 2. (Currently amended) An integrated circuit (IC) as claimed in claim 1, eharacterized in that wherein the tester further comprises detection means (CMP/ADC) for detecting the validity of the signal generated by the transmission channel (TX).
- 3. (Currently amended) An integrated circuit (IC) as claimed in claim 1, characterized in that wherein the tester further comprises a filter (F) for filtering harmonics of the signal.
- 4. (Currently amended) An integrated circuit (IC) as claimed in claim 1, characterized in that wherein the first frequency (F0) is a radio frequency and the second frequency (F1) is a low frequency.
- 5. (Currently amended) A method of testing an integrated circuit (IC) comprising a signal transmission channel (TX) including radio frequencies, said method being intended to

test radio characteristics of said integrated circuit and being independent of said transmission channel, said method comprising the following steps: recovering a part of the signal generated by the transmission channel (TX) at a first frequency (F0), converting the first frequency (F0) of the recovered signal into a second frequency (F1), amplifying said signal at this second frequency (F1), and rectifying said signal.

- 6. (Currently amended) A method of testing an integrated circuit (IC) as claimed in claim
- 5, characterized in that it further comprisinges a step of detecting the validity of the signal generated by the transmission channel-(TX).
- 7. (Currently amended) A method of testing an integrated circuit (IC) as claimed in claim
- 5, characterized in that it comprisinges a step of filtering harmonics of said signal.
- 8. (Currently amended) A tester (TEST) for testing radio characteristics of a transmission channel (TX) of an integrated circuit (IC), said tester (TEST) being intended to be integrated with said integrated circuit (IC) and comprising: first means (COUPL) for recovering a part of the signal generated by the transmission channel (TX) at a first frequency (F0) second means (M) for converting said signal recovered from the first frequency (F0) into a second frequency (F1) an amplifier (A) for amplifying said signal to this second frequency (F1), and a rectifier (R) for rectifying said signal.
- 9. (Currently amended) A tester as claimed by claim 8, characterized in that it further comprisinges detection means (CMP/ADC) for detecting the validity of the signal

generated by the transmission channel-(TX).

- 10. (Currently amended) A tester as claimed by claim 8, characterized in that it further comprisinges a filter (F) for filtering harmonics of said signal.
- 11. (Currently amended) A transmitter comprising an integrated circuit (IC) comprising a tester as claimed in claim 8.